

High Voltage Power MOSFET

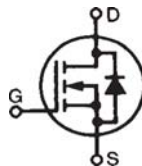
IXTF02N450

$$V_{DSS} = 4500V$$

$$I_{D25} = 200mA$$

$$R_{DS(on)} \leq 625\Omega$$

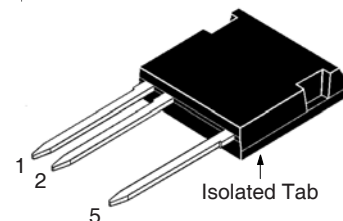
(Electrically Isolated Tab)



N-Channel Enhancement Mode

| Symbol | Test Conditions | Maximum Ratings | |
|---------------|---|-------------------|------------------|
| V_{DSS} | $T_J = 25^\circ\text{C}$ to 150°C | 4500 | V |
| V_{DGR} | $T_J = 25^\circ\text{C}$ to 150°C , $R_{GS} = 1M\Omega$ | 4500 | V |
| V_{GSS} | Continuous | ± 20 | V |
| V_{GSM} | Transient | ± 30 | V |
| I_{D25} | $T_C = 25^\circ\text{C}$ | 200 | mA |
| I_{DM} | $T_C = 25^\circ\text{C}$, Pulse Width Limited by T_{JM} | 600 | mA |
| P_D | $T_C = 25^\circ\text{C}$ | 78 | W |
| T_J | | - 55 ... +150 | $^\circ\text{C}$ |
| T_{JM} | | 150 | $^\circ\text{C}$ |
| T_{stg} | | - 55 ... +150 | $^\circ\text{C}$ |
| T_L | Maximum Lead Temperature for Soldering | 300 | $^\circ\text{C}$ |
| T_{SOLD} | Plastic Body for 10s | 260 | $^\circ\text{C}$ |
| F_C | Mounting Force | 20..120 / 4.5..27 | N/lb. |
| V_{ISOL} | 50/60Hz, 1 Minute | 4500 | V~ |
| Weight | | 6 | g |

ISOPLUS i4-Pak™



1 = Gate 5 = Drain
2 = Source

Features

- Silicon Chip on Direct-Copper Bond (DCB) Substrate
- Isolated Mounting Surface
- 4500V~ Electrical Isolation
- Molding Epoxies meet UL 94 V-0 Flammability Classification

Advantages

- High Voltage Package
- Easy to Mount
- Space Savings
- High Power Density

Applications

- High Voltage Power Supplies
- Capacitor Discharge Applications
- Pulse Circuits
- Laser and X-Ray Generation Systems

| Symbol | Test Conditions ($T_J = 25^\circ\text{C}$, Unless Otherwise Specified) | Characteristic Values | | |
|--------------|---|-----------------------|------|------------------|
| | | Min. | Typ. | Max. |
| $V_{GS(th)}$ | $V_{DS} = V_{GS}$, $I_D = 250\mu\text{A}$ | 4.0 | | 6.5 V |
| I_{GSS} | $V_{GS} = \pm 20V$, $V_{DS} = 0V$ | | | ± 100 nA |
| I_{DSS} | $V_{DS} = 3.6kV$, $V_{GS} = 0V$ | | | 5 μA |
| | $V_{DS} = 4.5kV$ | | | 10 μA |
| | $V_{DS} = 3.6kV$ Note 2, $T_J = 125^\circ\text{C}$ | | 15 | μA |
| $R_{DS(on)}$ | $V_{GS} = 10V$, $I_D = 10mA$, Note 1 | | | 625 Ω |

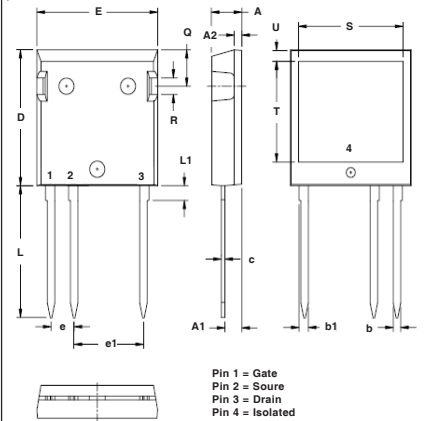
| Symbol | Test Conditions ($T_J = 25^\circ\text{C}$, Unless Otherwise Specified) | Characteristic Values | | |
|--------------|---|-----------------------|------|------------------------|
| | | Min. | Typ. | Max. |
| g_{fs} | $V_{DS} = 50\text{V}$, $I_D = 50\text{mA}$, Note 1 | 90 | 150 | mS |
| C_{iss} | $V_{GS} = 0\text{V}$, $V_{DS} = 25\text{V}$, $f = 1\text{MHz}$ | | 246 | pF |
| C_{oss} | | | 19 | pF |
| C_{rss} | | | 5.8 | pF |
| R_{Gi} | Gate Input Resistance | | 76 | Ω |
| $t_{d(on)}$ | Resistive Switching Times $V_{GS} = 10\text{V}$, $V_{DS} = 500\text{V}$, $I_D = 0.5 \cdot I_{D25}$ $R_G = 10\Omega$ (External) | | 17 | ns |
| t_r | | | 48 | ns |
| $t_{d(off)}$ | | | 28 | ns |
| t_f | | | 143 | ns |
| $Q_{g(on)}$ | $V_{GS} = 10\text{V}$, $V_{DS} = 1\text{kV}$, $I_D = 0.5 \cdot I_{D25}$ | | 10.6 | nC |
| Q_{gs} | | | 3.3 | nC |
| Q_{gd} | | | 5.5 | nC |
| R_{thJC} | | | | 1.6 $^\circ\text{C/W}$ |

Source-Drain Diode

| Symbol | Test Conditions ($T_J = 25^\circ\text{C}$, Unless Otherwise Specified) | Characteristic Values | | |
|----------|--|-----------------------|------|---------------|
| | | Min. | Typ. | Max. |
| I_s | $V_{GS} = 0\text{V}$ | | | 200 mA |
| I_{SM} | Repetitive, Pulse Width Limited by T_{JM} | | | 800 mA |
| V_{SD} | $I_F = I_s$, $V_{GS} = 0\text{V}$, Note 1 | | | 1.5 V |
| t_{rr} | $I_F = 200\text{mA}$, $-di/dt = 50\text{A}/\mu\text{s}$, $V_R = 100\text{V}$ | | 1.6 | μs |

- Notes: 1. Pulse test, $t \leq 300\mu\text{s}$, duty cycle, $d \leq 2\%$.
2. Part must be heatsunk for high-temp I_{DSS} measurement.

ISOPLUS i4-Pak™ (HV) Outline



| SYM | INCHES | | MILLIMETERS | |
|-----|----------|------|-------------|-------|
| | MIN | MAX | MIN | MAX |
| A | .190 | .205 | 4.83 | 5.21 |
| A1 | .102 | .118 | 2.59 | 3.00 |
| A2 | .046 | .085 | 1.17 | 2.16 |
| b | .045 | .055 | 1.14 | 1.40 |
| b1 | .058 | .068 | 1.47 | 1.73 |
| C | .020 | .029 | 0.51 | 0.74 |
| D | .819 | .840 | 20.80 | 21.34 |
| E | .770 | .799 | 19.56 | 20.29 |
| e | .150 BSC | | 3.81 BSC | |
| e1 | .450 BSC | | 11.43 BSC | |
| L | .780 | .840 | 19.81 | 21.34 |
| L1 | .083 | .102 | 2.11 | 2.59 |
| Q | .210 | .244 | 5.33 | 6.20 |
| R | .100 | .180 | 2.54 | 4.57 |
| S | .660 | .690 | 16.76 | 17.53 |
| T | .590 | .620 | 14.99 | 15.75 |
| U | .065 | .080 | 1.65 | 2.03 |

PRELIMINARY TECHNICAL INFORMATION

The product presented herein is under development. The Technical Specifications offered are derived from a subjective evaluation of the design, based upon prior knowledge and experience, and constitute a "considered reflection" of the anticipated result. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

IXYS Reserves the Right to Change Limits, Test Conditions, and Dimensions.

| | | | | | | | | | | |
|--|-----------|-----------|-----------|-----------|--------------|--------------|--------------|--------------|--------------|--------------|
| IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: | 4,835,592 | 4,931,844 | 5,049,961 | 5,237,481 | 6,162,665 | 6,404,065 B1 | 6,683,344 | 6,727,585 | 7,005,734 B2 | 7,157,338 B2 |
| | 4,860,072 | 5,017,508 | 5,063,307 | 5,381,025 | 6,259,123 B1 | 6,534,343 | 6,710,405 B2 | 6,759,692 | 7,063,975 B2 | |
| | 4,881,106 | 5,034,796 | 5,187,117 | 5,486,715 | 6,306,728 B1 | 6,583,505 | 6,710,463 | 6,771,478 B2 | 7,071,537 | |

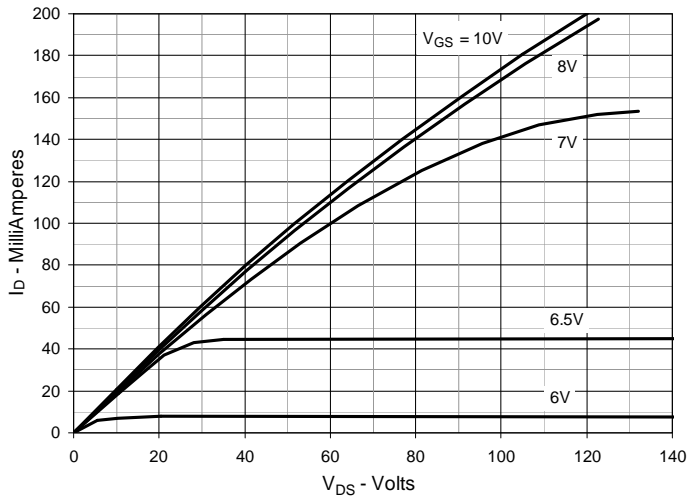
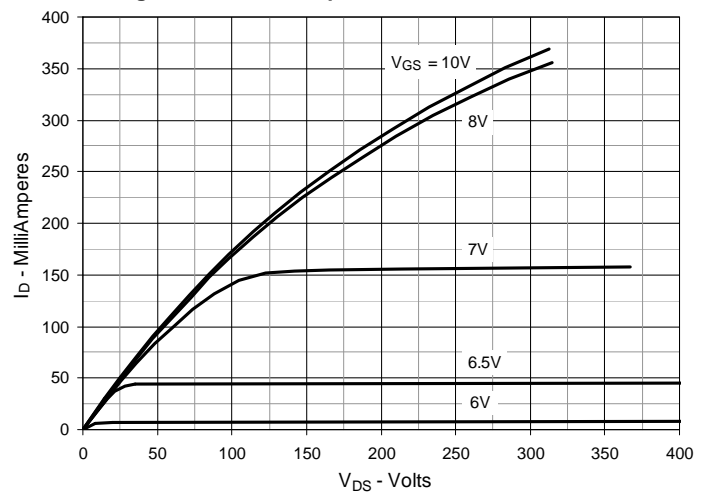
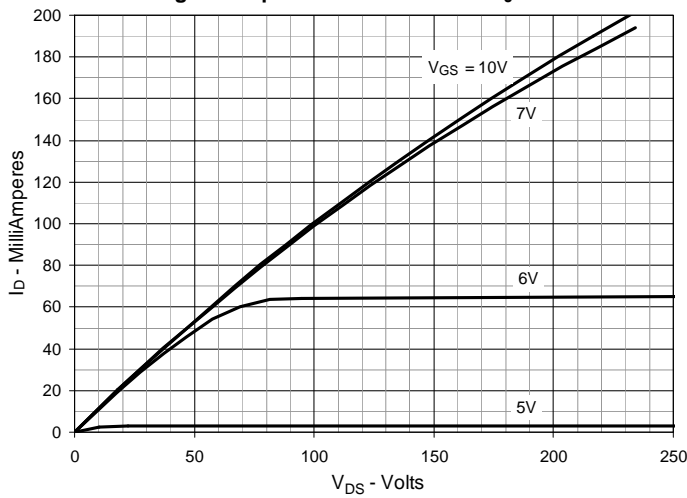
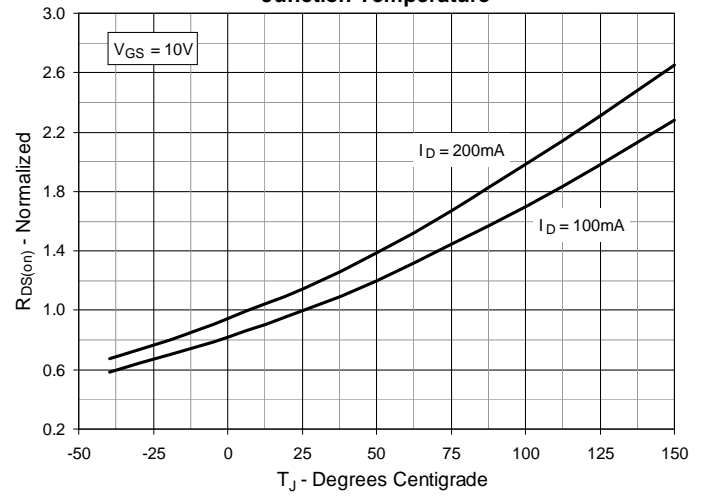
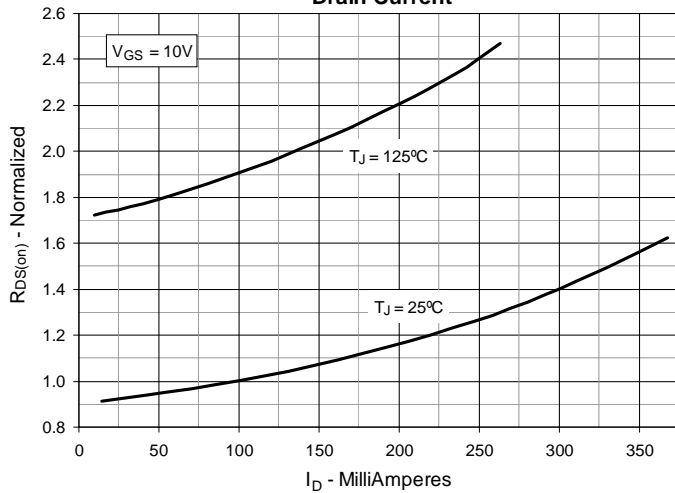
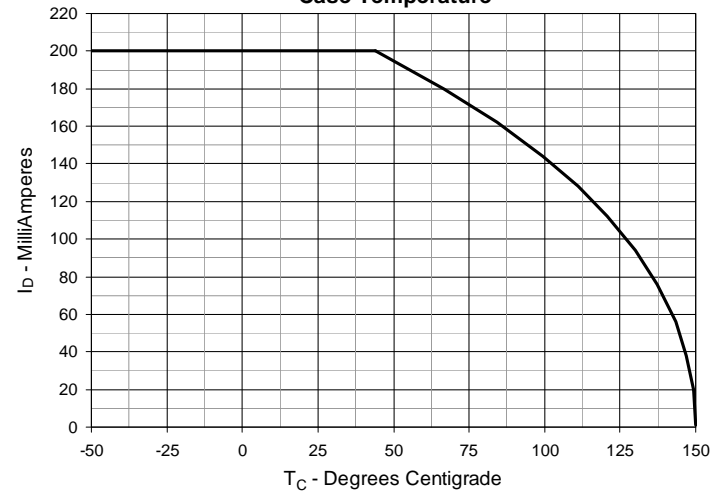
Fig. 1. Output Characteristics @ $T_J = 25^\circ\text{C}$

Fig. 2. Extended Output Characteristics @ $T_J = 25^\circ\text{C}$

Fig. 3. Output Characteristics @ $T_J = 125^\circ\text{C}$

Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 100\text{mA}$ Value vs. Junction Temperature

Fig. 5. $R_{DS(on)}$ Normalized to $I_D = 100\text{mA}$ Value vs. Drain Current

Fig. 6. Maximum Drain Current vs. Case Temperature


Fig. 7. Input Admittance

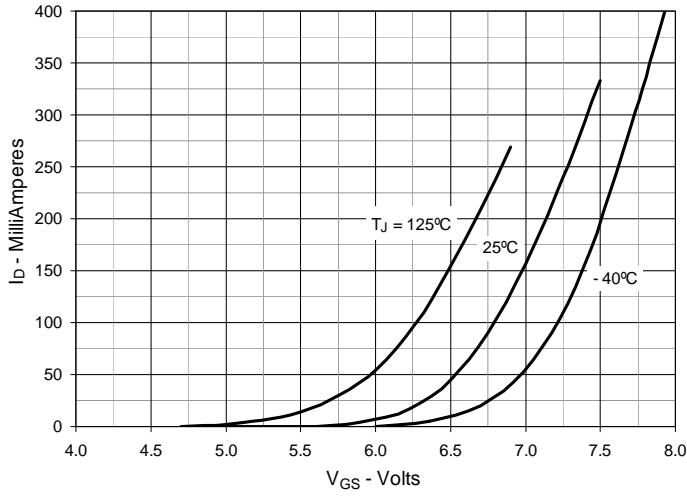


Fig. 8. Transconductance

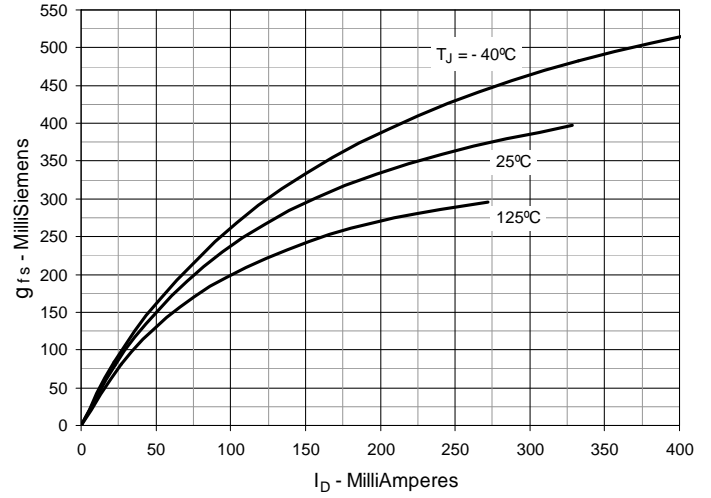


Fig. 9. Forward Voltage Drop of Intrinsic Diode

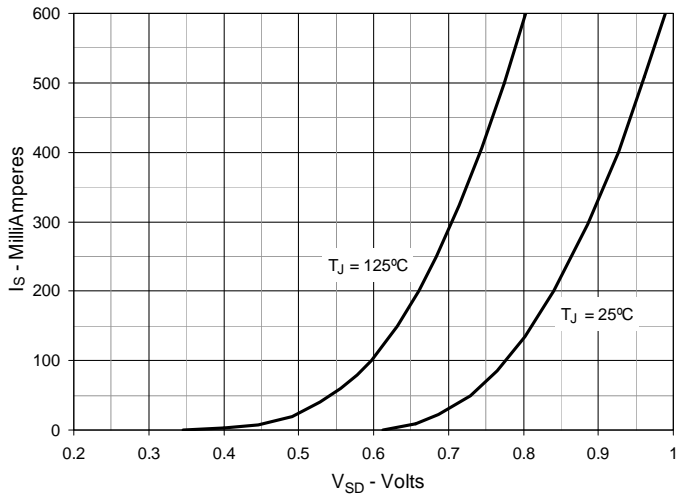


Fig. 10. Gate Charge

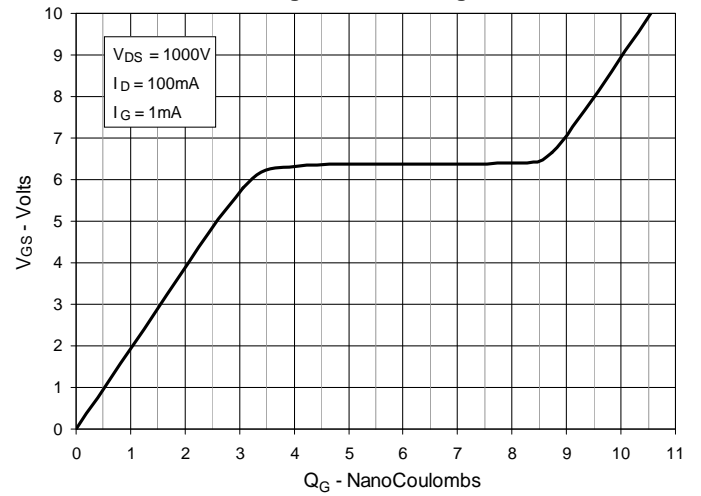


Fig. 11. Capacitance

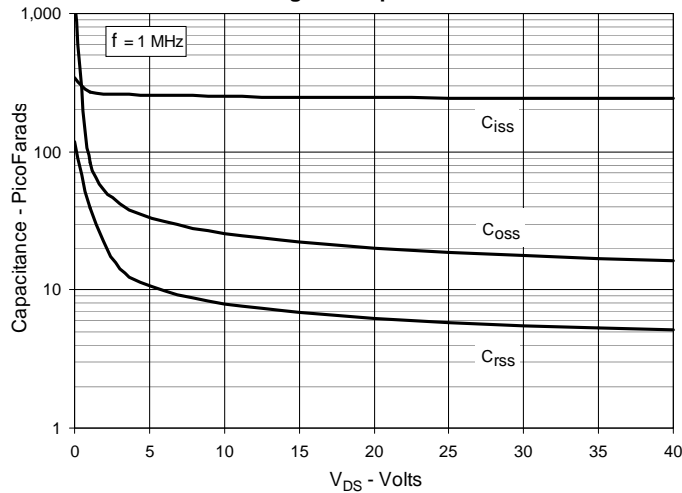


Fig. 12. Maximum Transient Thermal Impedance

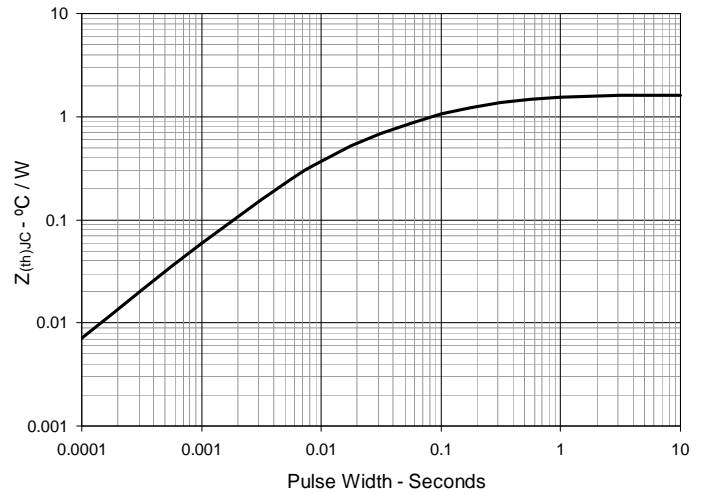


Fig. 13. Forward-Bias Safe Operating Area
@ $T_C = 25^\circ\text{C}$

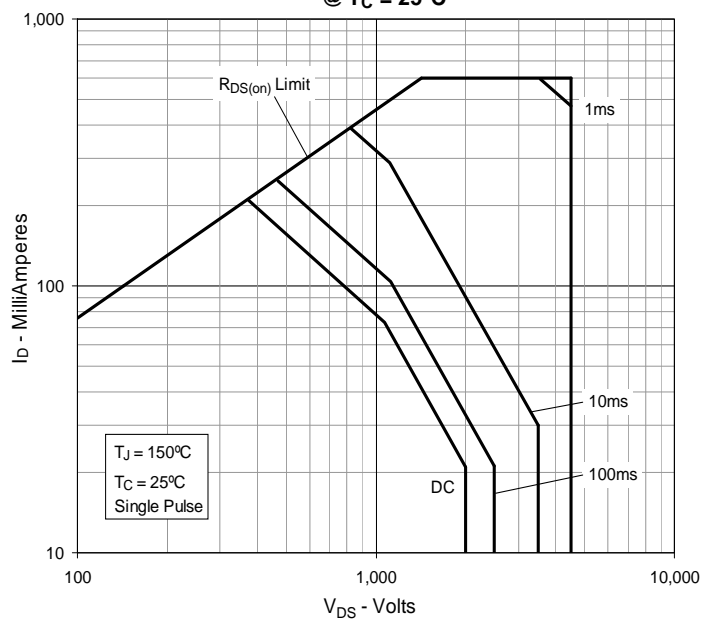
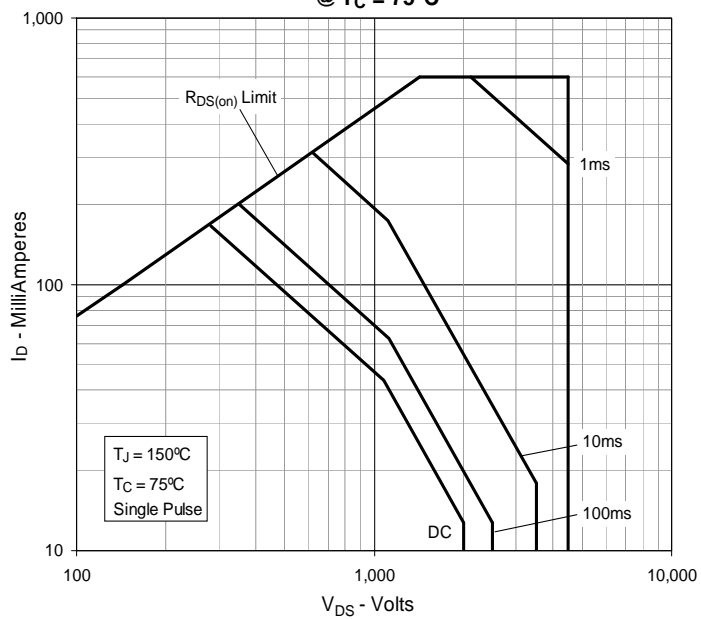


Fig. 14. Forward-Bias Safe Operating Area
@ $T_C = 75^\circ\text{C}$





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